


<b>Search Notes</b>  	<b>Application/Control No.</b>  10762330	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA, SATORU
	<b>Examiner</b>  BENJAMIN E LANIER	<b>Art Unit</b>  2432

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Limited Search of 726/2-15, 22-25 (See Attachment)	5/5/2011	BL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--